TOSHIBA Photocoupler GaAlAs Ired & Photo-IC

TLP112

Digital Logic Isolation

Line Receiver

Switching Power Supply Feedback Control

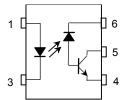
Transistor Inverter

The TOSHIBA mini flat coupler TLP112 is a small outline coupler, suitable for surface mount assembly.

TLP112 consists of a GaAlAs light emitting diode, optically coupled to a high speed detector of one chip photodiode–transistor.

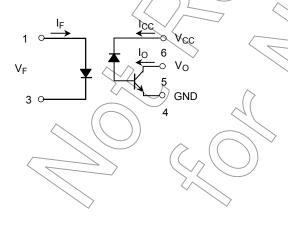
- Isolation voltage: 2500 Vrms (min.)
- Switching speed: $t_{pHL} = 0.8 \mu s$, $t_{pLH} = 2 \mu s (max.)$ ($R_L = 4.1 \ k\Omega$)
- TTL compatible
- UL recognized: UL1577, file no. E67349

Pin Configuration (top view)

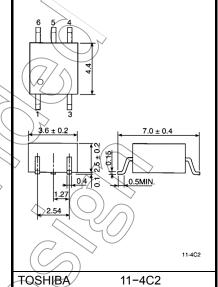


- 1 : ANODE
- 3 : CATHODE
- 4 : EMITTER (GND) 5 : COLLECTOR (OUTRUT)
- 6 : V_{CC}

Schematic



Unit in mm



Weight: 0.09 g (typ.)

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Absolute Maximum Ratings (Ta = 25°C)

	Characteristic		Symbol	Rating	Unit
LED	Forward current	(Note 1)	lF	25	mA
	Pulse forward current	(Note 2)	I _{FP}	50	mA
	Peak transient forward current	(Note 3)	I _{FPT}	1	А
	Reverse voltage		V _R	(5)	V
	Diode power dissipation	(Note 4)	PD	45	mW
Detector	Output current		<4Q ((// 8)	mA
	Peak output current		IOP	16	mA
	Supply voltage		Vçc	0.5~15	V
	Output voltage		VQ	-0.5~15	V
	Output power dissipation	(Note 5)	P ₀	100	mW
Operating temperature range		6	Topr	-55~100	\%C
Storage temperature range			T _{stg}	-55~125	°Ç
Lead soldering temperature(10s)			T _{sol}	260	(%)
Isolation voltage (AC, 1 min., R.H ≤ 60%,		Note 6)	BV _S	2500	Vrms

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

(Note 1) Derate 0.8 mA / °C above 70°C.

(Note 2) 50% duty cycle,1ms pulse width. Derate 1.6mA / °C/above 70°C.

(Note 3) Pulse width ≤ 1µs, 300pps.

(Note 4) Derate 0.9mW/ °C above 70°C.

(Note 5) Derate 2mW / C above 70°C.



Electrical Characteristics (Ta = 25°C)

Characteristic		Symbol	Test Condition	Min.	Тур.	Max.	Unit	
CED	Forward voltage	V _F	I _F = 16mA	_	1.65	1.85	V	
	Forward voltage temperature coefficient	ΔV _F / ΔTa	I _F = 16mA	_	-2	_	mV / °C	
	Reverse current	I _R	V _R = 5V	7	_	10	μΑ	
	Capacitance between terminals	C _T	V _F = 0, f = 1MHz		45	_	pF	
	High level output current	I _{OH (1)}	I _F = 0mA, V _{CC} = V _O = 5.5V	__\	3	500	nA	
or		I _{OH} (2)	I _F = 0mA, V _{CC} = V _O = 15V	()	_	5		
Detector		Іон	I _F = 0mA, V _{CC} = V _O = 15V Ta = 70°C	-	_	50	μΑ	
	High level supply current	ICCH	I _F = 0mA, V _{CC} = 15V	_	0.01	1	μΑ	
	Current transfer ratio	1 ₀ / 1 _F	I _F =16mA, V _{CC} = 4:5V V _O = 0.4V	10	1/2	<u>\</u>	%	
Coupled	Low level output voltage	V _{OL}	I _F = 16 mA, V _{OC} = 4.5V I _O = 1.1mA)	0.4	V	
	Isolation resistance	R _S	R.H. ≤ 60% V _S = 500V DC (Note 6)	5×10 ¹⁰	1014	_	Ω	
	Stray capacitance between input to output	CS	$V_S = 0, f = 1 MHz$ (Note 6)		0.8	_	pF	

Switching Characteristics (Ta = 25°C)

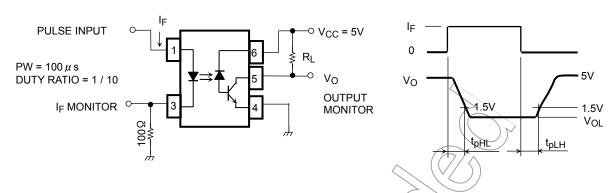
Characteristic	Symbol	Test Cir- cuit	Test Condition	Min.	Тур.	Max.	Unit
Propagation delay time (H→L)	tpHL	1	$I_F = 0 \rightarrow 16 \text{mA}$ $V_{CC} = 5V$, $R_L = 4.1 \text{k}\Omega$	_	-	0.8	μs
Propagation delay time (L→H)	T tpLH	1	$I_F = 16 \rightarrow 0$ mA $V_{CC} = 5V$, $R_L = 4.1$ kΩ	-	-	2.0	μs
Common mode transient immunity at high output level	CMH	2	$V_{E} = 0 \text{mA}, V_{CM} = 200 V_{p-p}$ $R_{L} = 4.1 \text{k}\Omega$		1500		V / µs
Common mode transient immunity at low output level	CML	2	L_E =16mA, V_{CM} = 200 V_{p-p} R _L = 4.1kΩ	ı	-1500	ı	V / µs

(Note 6) Device considered a two–terminal device: Pins 1 and 3 shorted together and Pin 4, 5 and 6 shorted together.

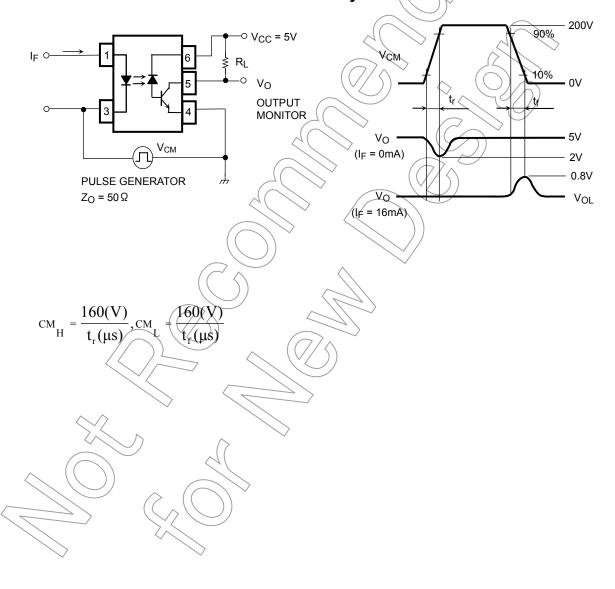
(Note 7) Maximum electrostatic discharge voltage for any pins: 100V (C=200pF, R=0)

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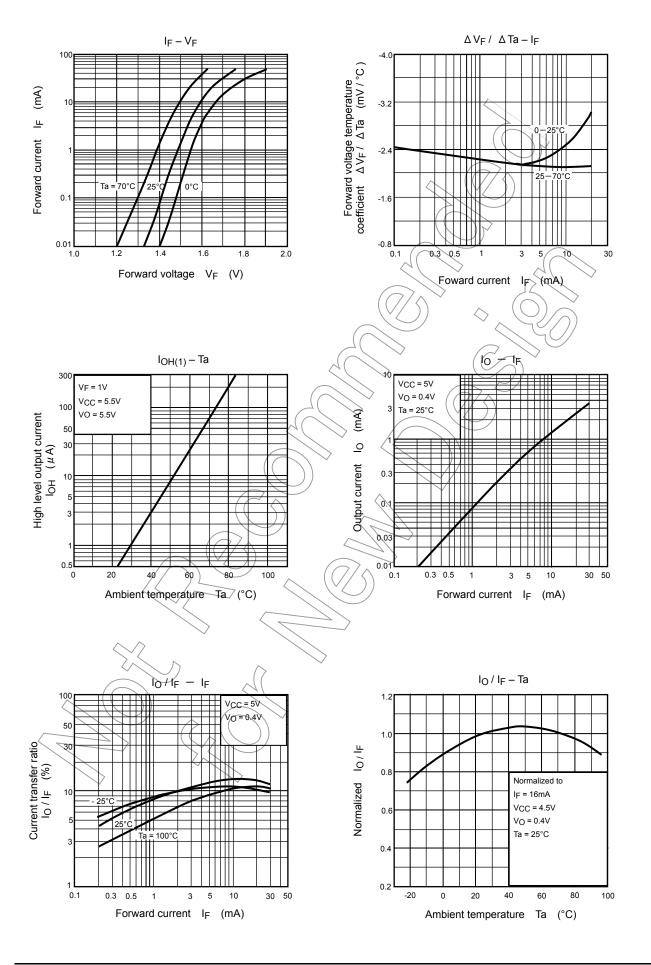
Test Circuit 1: Switching Time Test Circuit

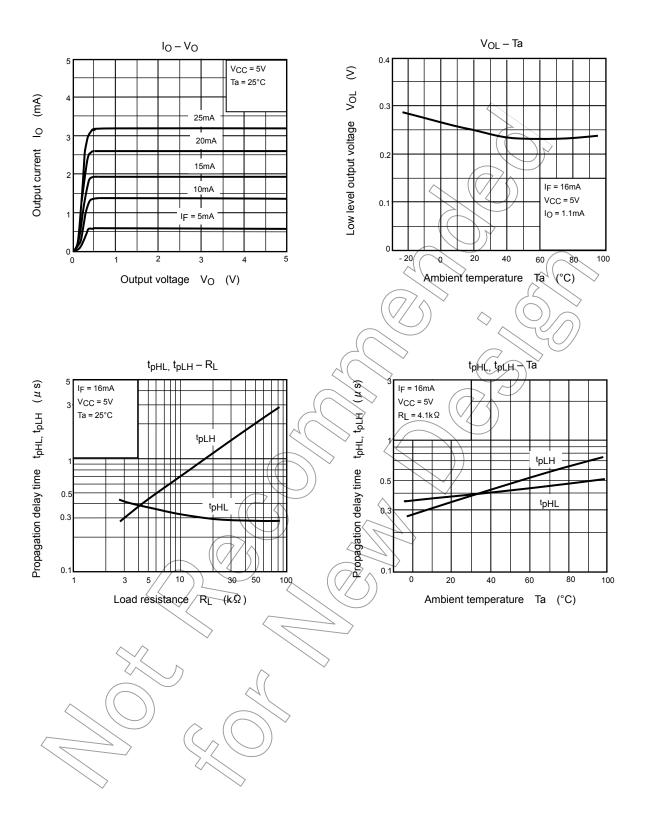


Test Circuit 2: Common Mode Transient Immunity Test Circuit



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